

## **Documents**

Aziz, S.G.<sup>a b</sup>, Vela, M.E.<sup>a</sup>, Andreasen, G.<sup>a</sup>, Salvarezza, R.C.<sup>a</sup>, Hernández-Creus, A.<sup>a c</sup>, Arvia, A.J.<sup>a</sup> Sequential in situ STM imaging of electrodissolving copper single-crystal domains in aqueous perchloric acid: Kinetics and mechanism of the interface evolution

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## Abstract

The evolution of Cu crystal surfaces in an aqueous perchloric acid solution at both null (j=0) and constant anodic apparent current density (j=6  $\mu$ A cm-2) at room temperature was followed by in situ scanning tunneling microscopy sequential imaging. For j=0, the Cu surface turns out to be highly dynamic as terrace growth step displacement, and smoothening of small pits can be observed. These processes lead to a small decrease in the value of the root-mean-square roughness ( $\xi$ ). On the other hand, for j=6  $\mu$ A cm-2, an inhomogeneous attack proceeds with a marked increase in  $\xi$ . In this case, while some surface domains become progressively rough others develop nm-sized etched pits that turn the interface unstable. The evolution of the Cu topography under the experimental conditions of this work was simulated using a Monte Carlo algorithm based on a dissolution model in which surface processes are influenced by inhomogeneity stabilizing cavities.

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